

## General Description

FSMOS<sup>®</sup>

$R_{DS(ON)}$ , low gate charge, fast switching and excellent avalanche characteristics. The low  $V_{th}$  series is specially optimized for synchronous rectification systems with low driving voltage.

## Features

- Low  $R_{DS(ON)}$  & FOM (Figure of Merit)
- Extremely low switching loss
- Excellent reliability and uniformity
- Fast switching and soft recovery



## Applications

- Consumer electronic power supply
- Motor control
- Synchronous rectification
- Isolated DC/DC convertor
- Invertors

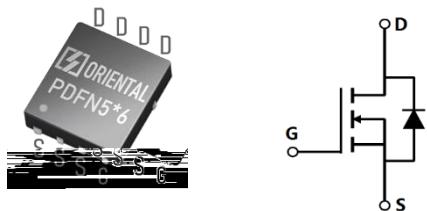
## Key Performance Parameters

Parameter	Value	Unit
$V_{DS, min} @ T_{j(max)}$	60	V
$I_D, pulse$	480	A
$R_{DS(ON) max} @ V_{GS}=10V$	2.3	
$Q_g$	109.6	nC

## Marking Information

Product Name	Package	Marking
SFS06R02UGF	PDFN5*6	SFS06R02UG

## Package & Pin information



**Absolute Maximum Ratings** at  $T_j=25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	$V_{DS}$	60	V
Gate source voltage	$V_{GS}$	$\pm 20$	V
Continuous drain current <sup>1)</sup> , $T_C=25^\circ\text{C}$	$I_D$	160	A
Pulsed drain current <sup>2)</sup> , $T_C=25^\circ\text{C}$	$I_{D,\text{pulse}}$	480	A
Continuous diode forward current <sup>1)</sup> , $T_C=25^\circ\text{C}$	$I_S$	160	A
Diode pulsed current <sup>2)</sup> , $T_C=25^\circ\text{C}$	$I_{S,\text{Pulse}}$	480	A
Power dissipation <sup>3)</sup> , $T_C=25^\circ\text{C}$	$P_D$	132	W
Single pulsed avalanche energy <sup>5)</sup>	$E_{AS}$	453	mJ
Operation and storage temperature	$T_{stg} \quad T_i$	-55 to 150	$^\circ\text{C}$

**Thermal Characteristics**

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	R	0.95	$^\circ\text{C}/\text{W}$
Thermal resistance, junction-ambient <sup>4)</sup>	R	62	$^\circ\text{C}/\text{W}$

**Electrical Characteristics** at  $T_j=25^\circ\text{C}$  unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	$BV_{DSS}$	60			V	$V_{GS}=0 \text{ V}, I_D=250 \text{ A}$
Gate threshold voltage	$V_{GS(\text{th})}$	1.2		2.5	V	$V_{DS}=V_{GS}, I_D=250 \text{ A}$
Drain-source on-state resistance	$R_{DS(\text{ON})}$		2.0	2.3		$V_{GS}=10 \text{ V}, I_D=50 \text{ A}$
Drain-source on-state resistance	$R_{DS(\text{ON})}$		2.6	3.0		$V_{GS}=4.5 \text{ V}, I_D=30 \text{ A}$
Gate-source leakage current	$I_{GSS}$			100	nA	$V_{GS}=20 \text{ V}$
				-100		$V_{GS}=-20 \text{ V}$
Drain-source leakage current	$I_{DSS}$			1	A	$V_{DS}=60 \text{ V}, V_{GS}=0 \text{ V}$
Gate resistance	$R_G$		1.95			

### Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C <sub>iss</sub>		6851		pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =25 V, kHz
Output capacitance	C <sub>oss</sub>		1254		pF	
Reverse transfer capacitance	C <sub>rss</sub>		68.6		pF	
Turn-on delay time	t <sub>d(on)</sub>		29.2		ns	V <sub>GS</sub> =10 V, V <sub>DS</sub> =50 V, R <sub>G</sub> I <sub>D</sub> =50 A
Rise time	t <sub>r</sub>		67.6		ns	
Turn-off delay time	t <sub>d(off)</sub>		90.8		ns	
Fall time	t <sub>f</sub>		23.6		ns	

### Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q <sub>g</sub>		109.6		nC	V <sub>GS</sub> =10 V V <sub>DS</sub> =50 V, I <sub>D</sub> =50 A,
Gate-source charge	Q <sub>gs</sub>		17.6		nC	
Gate-drain charge	Q <sub>gd</sub>		21.7		nC	
Gate plateau voltage	V <sub>plateau</sub>		3.4		V	

### Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V <sub>SD</sub>			1.3	V	I <sub>S</sub> =20 A, V <sub>GS</sub> =0 V
Reverse recovery time	t <sub>rr</sub>		80		ns	V <sub>R</sub> =50 V, I <sub>S</sub> =50 A,
Reverse recovery charge	Q <sub>rr</sub>		131.7		nC	
Peak reverse recovery current	I <sub>rrm</sub>		2.8		A	

### Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of R<sub>d</sub> is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>a</sub>=25 °C.
- 5) V<sub>DD</sub>=30 V, V<sub>G</sub>=10 V, L=0.3 mH, starting T<sub>j</sub>=25 °C.

## Electrical Characteristics Diagrams

Figure 1. Typ. output characteristics

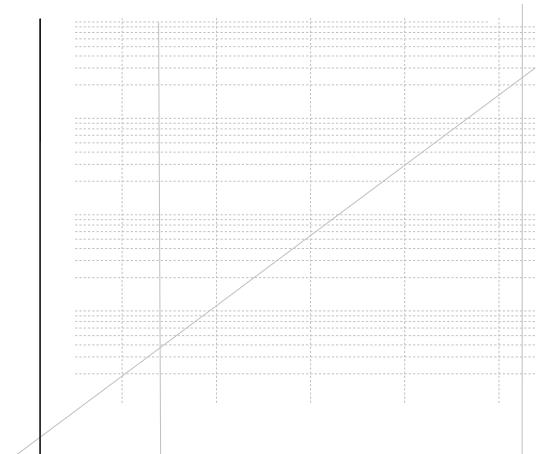


Figure 2. Typ. transfer characteristics

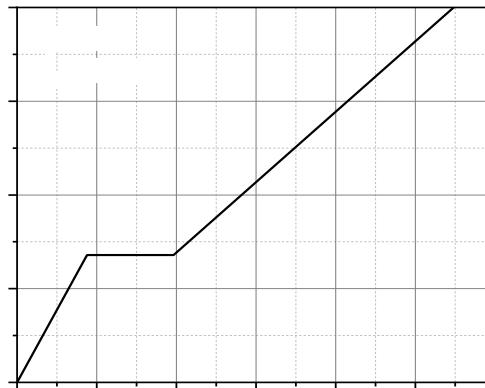


Figure 3. Typ. capacitances

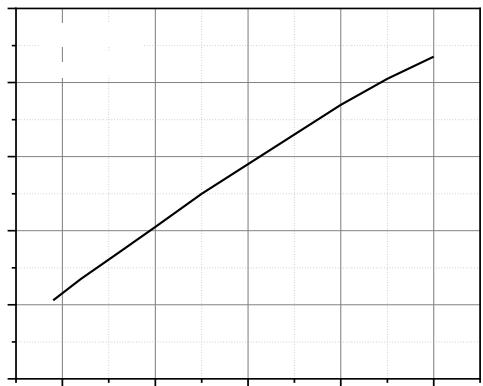


Figure 5. Drain-source breakdown voltage

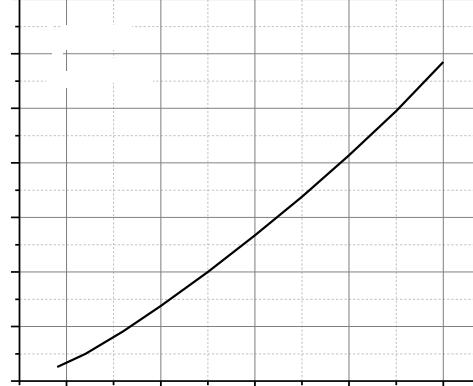
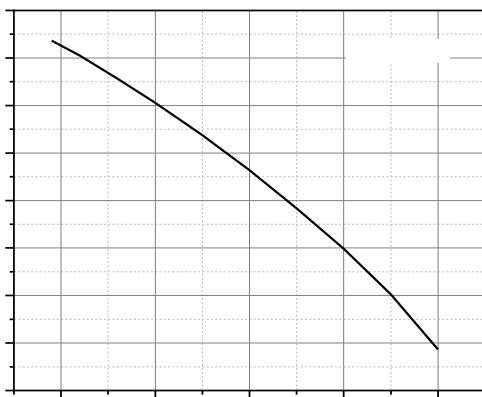
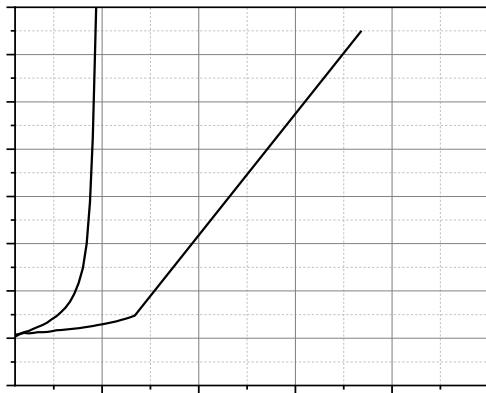
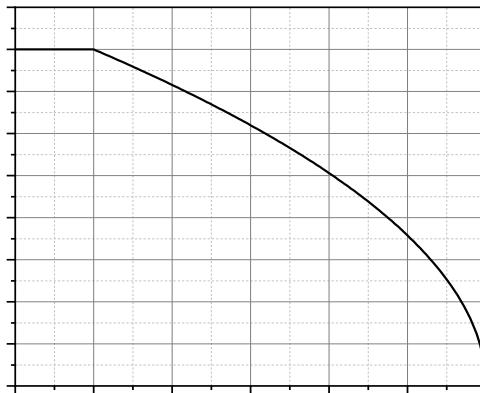
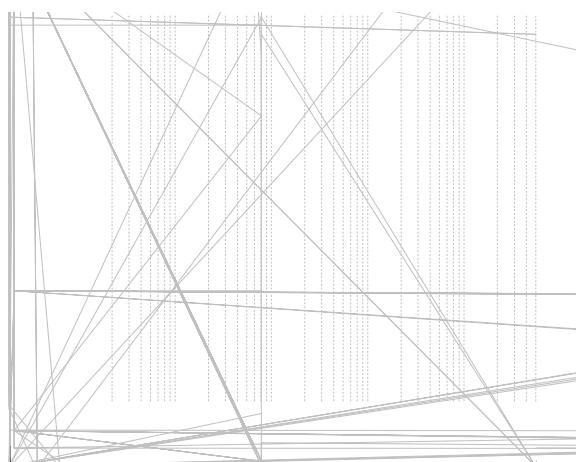
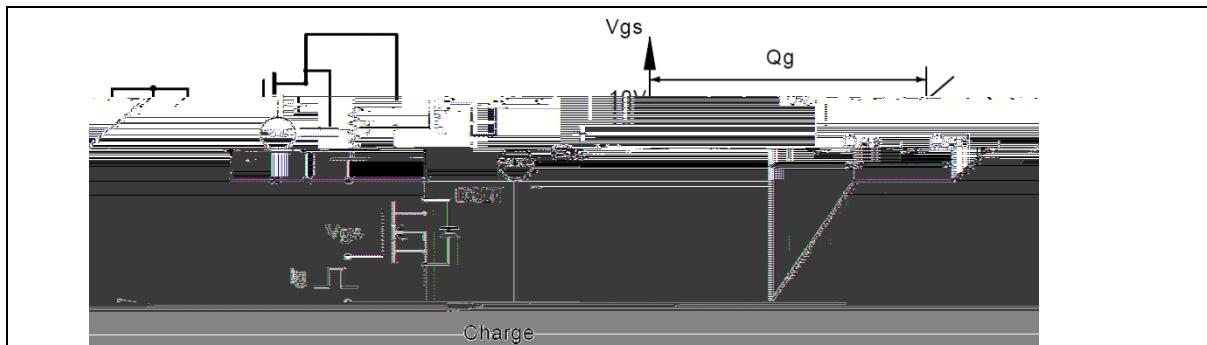


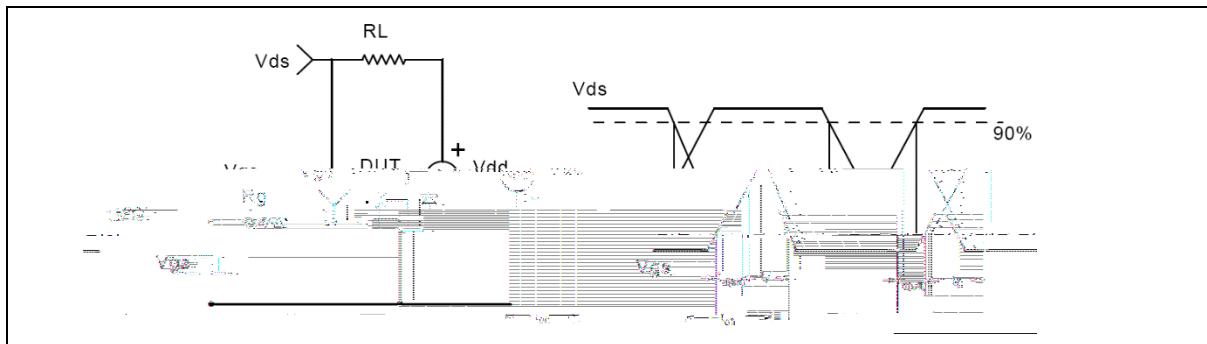
Figure 6. Drain-source on-state resistance

**Figure 7. Threshold voltage****Figure 8. Forward characteristic of body diode****Figure 9. Drain-source on-state resistance****Figure 10. Drain current****Figure 11. Safe operation area  $T_c=25\text{ °C}$** **Figure 12. Max transient thermal impedance**

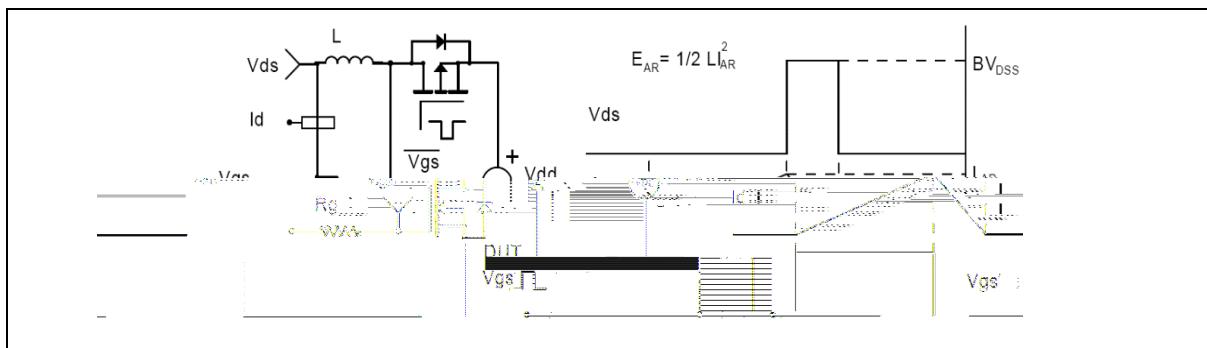
### Test circuits and waveforms



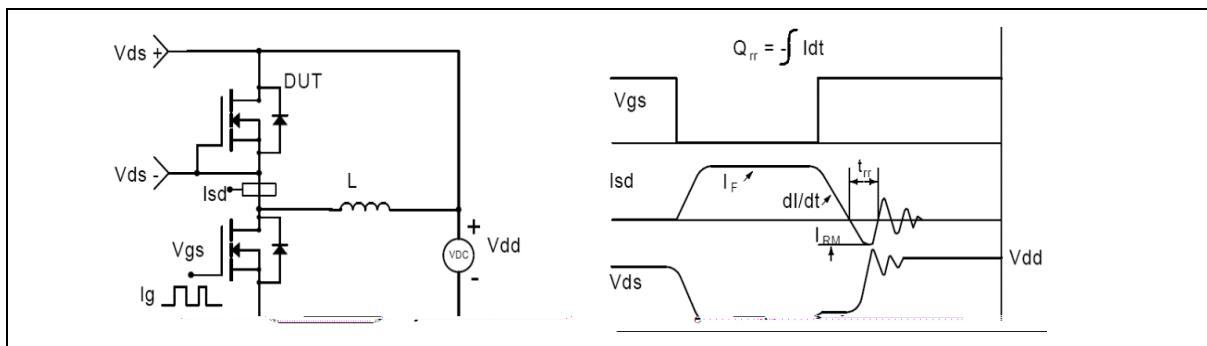
**Figure 1. Gate charge test circuit & waveform**



**Figure 2. Switching time test circuit & waveform**



**Figure 3. Unclamped inductive switching (UIS) test circuit & waveform**



**Figure 4. Diode reverse recovery test circuit & waveform**

**SFS06R02UGF**

Enhancement Mode N

## Ordering Information

Package Type	Units/Reel	Reels / Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
PDFN5*6	5000	2	10000	5	50000

## Product Information

Product	Package	Pb Free	RoHS	Halogen Free
SFS06R02UGF	PDFN5*6	yes	yes	yes

## Legal Disclaimer

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